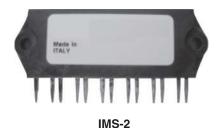
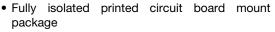


IGBT SIP Module (Ultrafast IGBT)



PRODUCT SUMMARY					
OUTPUT CURRENT IN A TYPICAL 20 kHz MOTOR DRIVE					
I_{RMS} per phase (3.5 kW total) with $T_C = 90 ^{\circ}C$	12 A _{RMS}				
T_J	125 °C				
Supply voltage	360 V _{DC}				
Power factor	0.8				
Modulation depth (see fig. 1)	115 %				
V _{CE(on)} (typical) at I _C = 10 A, 25 °C	1.56 V				
Package	SIP				
Circuit	Three Phase Inverter				

FEATURES





· Switching-loss rating includes all "tail" losses

COMPLIANT

- HEXFRED® soft ultrafast diodes
- Optimized for high speed over 5 kHz
 See fig. 1 for current vs. frequency curve
- UL approved file E78996
- · Designed and qualified for industrial level
- Material categorization: For definitions of compliance please see <u>www.vishay.com/doc?99912</u>

DESCRIPTION

The IGBT technology is the key to Vishay's Semiconductors advanced line of IMS (Insulated Metal Substrate) power modules. These modules are more efficient than comparable bipolar transistor modules, while at the same time having the simpler gate-drive requirements of the familiar power MOSFET. This superior technology has now been coupled to a state of the art materials system that maximizes power throughput with low thermal resistance. This package is highly suited to motor drive applications and where space is at a premium.

ABSOLUTE MAXIMUM RATINGS					
PARAMETER	SYMBOL	TEST CONDITIONS	MAX.	UNITS	
Collector to emitter voltage	V _{CES}		600	V	
Continuous collector current, each IGBT		T _C = 25 °C	20		
Continuous collector current, each IGB1	I _C	T _C = 100 °C	10		
Pulsed collector current	I _{CM} ⁽¹⁾		60	A	
Clamped inductive load current	I _{LM} ⁽²⁾		60		
Diode continuous forward current	I _F	T _C = 100 °C	9.3		
Diode maximum forward current	I _{FM}		60		
Gate to emitter voltage	V_{GE}		± 20	V	
Isolation voltage	V _{ISOL}	t = 1 min, any terminal to case	2500	V _{RMS}	
Marian and distinction and IODT	В	T _C = 25 °C	63	w	
Maximum power dissipation, each IGBT	P _D	T _C = 100 °C	25		
Operating junction and storage temperature range	T _J , T _{Stg}		- 40 to + 150	°C	
Soldering temperature		For 10 s, (0.063" (1.6 mm) from case)	300		
Mounting torque		6-32 or M3 screw	5 to 7 (0.55 to 0.8)	lbf · in (N · m)	

Notes

⁽¹⁾ Repetitive rating; V_{GE} = 20 V, pulse width limited by maximum junction temperature (see fig. 20)

 $^{^{(2)}~}V_{CC}$ = 80 % (V_{CES}), V_{GE} = 20 V, L = 10 $\mu\text{H},~R_{G}$ = 10 Ω (see fig. 19)





THERMAL AND MECHANICAL SPECIFICATIONS					
PARAMETER	SYMBOL	TYP.	MAX.	UNITS	
Junction to case, each IGBT, one IGBT in conduction	R _{thJC} (IGBT)	-	2.0		
Junction to case, each DIODE, one DIODE in conduction	R _{thJC} (DIODE)	-	3.0	°C/W	
Case to sink, flat, greased surface	R _{thCS} (MODULE)	0.10	-		
Weight of module		20	-	g	
weight of module		0.7	-	oz.	

ELECTRICAL SPECIFICATIONS (T _J = 25 °C unless otherwise specified)							
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNITS
Collector to emitter breakdown voltage	V _{(BR)CES} (1)	$V_{GE} = 0 \text{ V}, I_{C} = 250 \mu\text{A}$	V _{GE} = 0 V, I _C = 250 μA		-	-	V
Temperature coefficient of breakdown voltage	$\Delta V_{(BR)CES}/\Delta T_J$	V _{GE} = 0 V, I _C = 1.0 mA		ı	0.63	-	V/°C
	V _{CE(on)}	I _C = 10 A		ı	1.56	2.1	V
Collector to emitter saturation voltage		I _C = 20 A	V _{GE} = 15 V	-	1.84	-	
Ç	32(0.1)	I _C = 10 A, T _J = 150 °C	See fig. 2, 5	-	1.56	-	
Gate threshold voltage	V _{GE(th)}	$V_{CE} = V_{GE}$, $I_C = 250 \mu A$	3.0	-	6.0		
Temperature coefficient of threshold voltage	$\Delta V_{GE(th)}/\Delta T_{J}$	V _{CE} = V _{GE} , I _C = 250 μA		-	- 13	-	mV/°C
Forward transconductance	g _{fe} ⁽²⁾	V _{CE} = 100 V, I _C = 10 A		11	18	-	S
	ICES	$V_{GE} = 0 \text{ V}, V_{CE} = 600 \text{ V}$		-	-	250	
Zero gate voltage collector current		V _{GE} = 0 V, V _{CE} = 600 V, T _J = 150 °C		-	-	3500	μΑ
Diode forward voltage drop	V _{FM}	I _C = 15 A	Coofie 10	-	1.3	1.7	٧
		I _C = 15 A, T _J = 150 °C	See fig. 13	-	1.2	1.6	
Gate to emitter leakage current	I _{GES}	V _{GE} = ± 20 V		-	-	± 100	nA

Notes

 $^{^{(1)}~}$ Pulse width $\leq 80~\mu s,~duty~factor \leq 0.1~\%$

 $^{^{(2)}}$ Pulse width 5.0 μ s; single shot





PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNITS		
Total gate charge (turn-on)	Qg	I _C = 10 A		-	100	160	nC		
Gate to emitter charge (turn-on)	Q _{ge}	$V_{CC} = 400 \text{ V}$ $V_{GE} = 15 \text{ V}$		-	16	24			
Gate to collector charge (turn-on)	Q _{gc}	See fig. 8			-	40	55	1	
Turn-on delay time	t _{d(on)}				-	41	-		
Rise time	t _r	T _J = 25 °C			-	13	-		
Turn-off delay time	t _{d(off)}	I _C = 10 A, V _C			-	96	140	ns	
Fall time	t _f	V _{GE} = 15 V, F	$R_G = 10 \Omega$ s include "tail"	and diode	-	110	160		
Turn-on switching loss	E _{on}	reverse recov		and diode	-	0.26	-	mJ	
Turn-off switching loss	E _{off}	See fig. 9, 10), 11, 18		-	0.18	-		
Total switching loss	E _{ts}					0.44	0.7	1	
Turn-on delay time	t _{d(on)}	T _{.1} = 150 °C				39	-		
Rise time	t _r	I_{C} = 10 A, V_{CC} = 480 V V_{GE} = 15 V, R_{G} = 10 Ω Energy losses include "tail" and diode reverse recovery See fig. 9, 10, 11, 18			-	15	-	ns ns	
Turn-off delay time	t _{d(off)}				-	220	-		
Fall time	t _f				-	160	-		
Total switching loss	E _{ts}				-	0.74	-	mJ	
Input capacitance	C _{ies}	$V_{GE} = 0 \text{ V}$ $V_{CC} = 30 \text{ V}$ $f = 1.0 \text{ MHz}$			-	2100	-		
Output capacitance	C _{oes}				-	110	-	рF	
Reverse transfer capacitance	C _{res}	See fig. 7			-	34	-		
Diede ee ee ee		T _J = 25 °C	See fig. 14		-	42	60		
Diode reverse recovery time	t _{rr}	T _J = 125 °C		See fig. 14		-	74	120	ns
Diada analysis and an analysis	Im	T _J = 25 °C	0 5 15		-	4.0	6.0	^	
Diode peak reverse recovery charge		T _J = 125 °C	See fig. 15	I _F = 15 A	-	6.5	10	A	
Die de verse verse verse de verse	0	T _J = 25 °C	See fig. 16	V _R = 200 V dI/dt = 200 A/μs	-	80	180	nC	
Diode reverse recovery charge	Q _{rr}	T _J = 125 °C			-	220	600	nC	
Diode peak rate of fall of	الم الم	T _J = 25 °C		-	188	-	Λ /		
recovery during t _b	dl _{(rec)M} /dt	T _J = 125 °C	See fig. 17	See fig. 17		-	160	-	A/µs

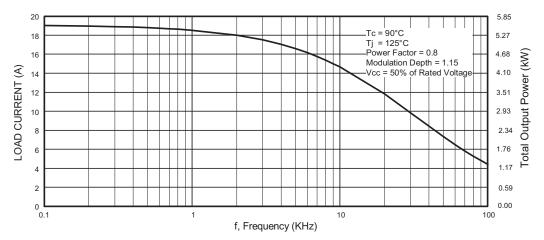


Fig. 1 - Typical Load Current vs. Frequency (Load Current = I_{RMS} of Fundamental)

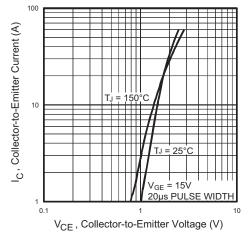


Fig. 2 - Typical Output Characteristics

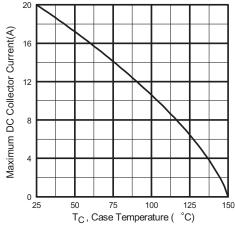


Fig. 4 - Maximum Collector Current vs. Case Temperature

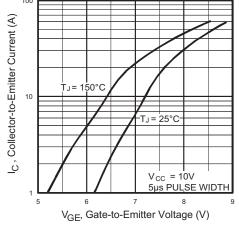


Fig. 3 - Typical Transfer Characteristics

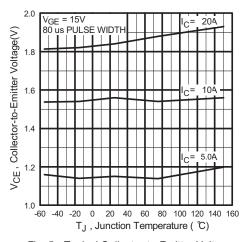


Fig. 5 - Typical Collector to Emitter Voltage vs. Junction Temperature



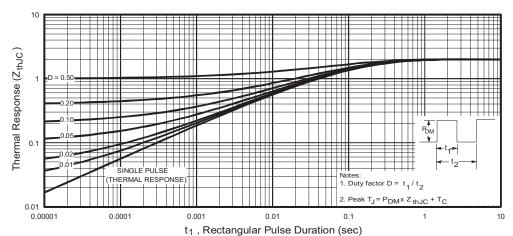


Fig. 6 - Maximum Effective Transient Thermal Impedance, Junction to Case

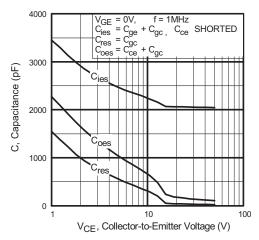


Fig. 7 - Typical Capacitance vs. Collector to Emitter Voltage

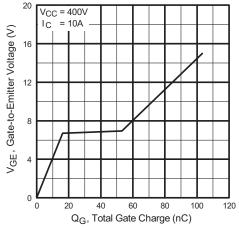


Fig. 8 - Typical Gate Charge vs. Gate to Emitter Voltage

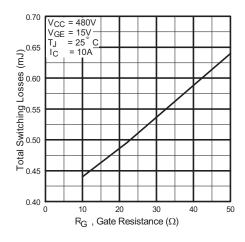


Fig. 9 - Typical Switching Losses vs. Gate Resistance

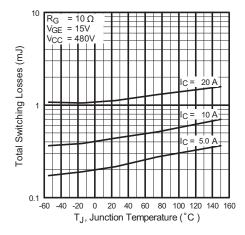


Fig. 10 - Typical Switching Losses vs. Junction Temperature



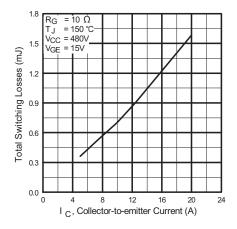


Fig. 11 - Typical Switching Losses vs. Collector to Emitter Current

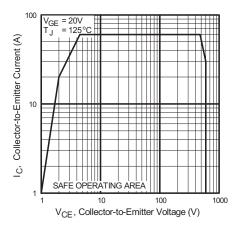


Fig. 12 - Turn-Off SOA

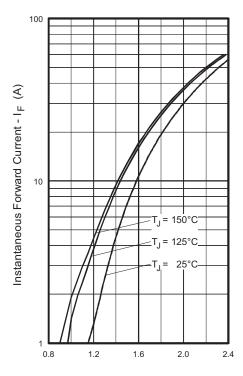


Fig. 13 - Maximum Forward Voltage Drop vs. Instantaneous Forward Current

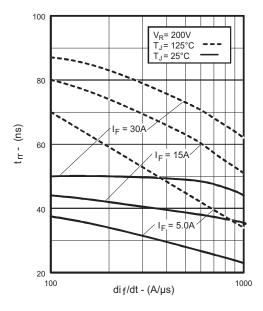


Fig. 14 - Typical Reverse Recovery Time vs. dl_F/dt

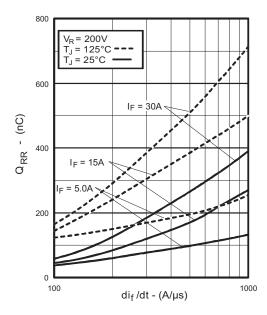


Fig. 16 - Typical Stored Charge vs. dl_F/dt

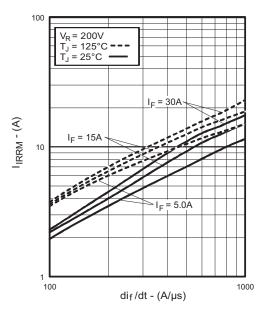


Fig. 15 - Typical Recovery Current vs. dI_F/dt

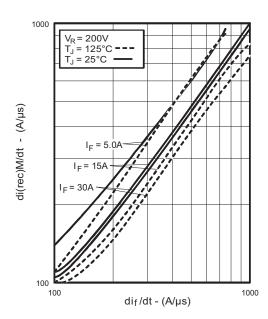


Fig. 17 - Typical $dI_{(rec)M}/dt$ vs dI_F/dt



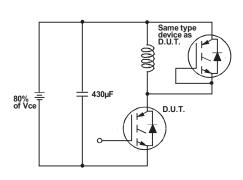


Fig. 18a - Test Circuit for Measurement of I_{LM} , E_{on} , $E_{off(diode)}$, t_{rr} , Q_{rr} , I_{rr} , $t_{d(on)}$, t_r , $t_{d(off)}$, t_f

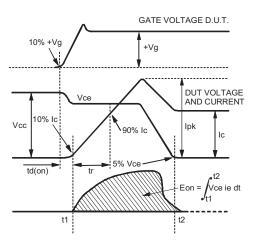


Fig. 18c - Test Waveforms for Circuit of Fig. 18a, Defining E_{on} , $t_{d(on)}$, t_{r}

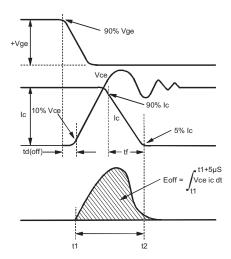


Fig. 18b - Test Waveforms for Circuit of Fig. 18a, Defining $E_{\rm off}$, $t_{\rm d(off)}$, $t_{\rm f}$

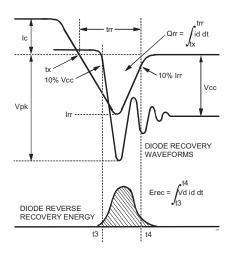


Fig. 18d - Test Waveforms for Circuit of Fig. 18a, Defining $E_{rec},\,t_{rr},\,Q_{rr},\,I_{rr}$

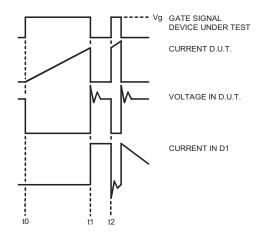
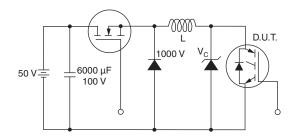


Fig. 18e - Macro Waveforms for Figure 18a's Test Circuit





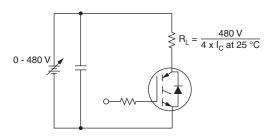
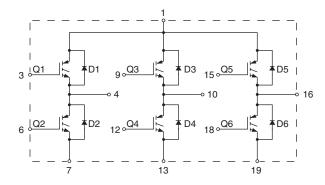


Fig. 19 - Clamped Inductive Load Test Circuit

Fig. 20 - Pulsed Collector Current Test Circuit

CIRCUIT CONFIGURATION

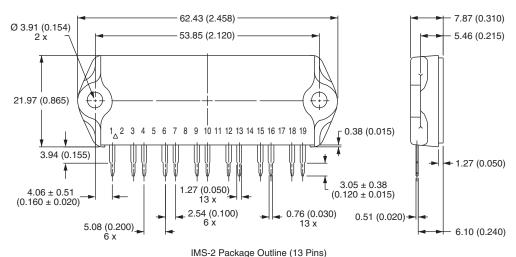


LINKS TO RELATED DOCUMENTS				
Dimensions	www.vishay.com/doc?95066			



IMS-2 (SIP)

DIMENSIONS in millimeters (inches)



INIS-2 Fackage Outline (13 Fil

Notes

- $^{(1)}$ Tolerance uless otherwise specified \pm 0.254 mm (0.010")
- (2) Controlling dimension: inch
- (3) Terminal numbers are shown for reference only

Document Number: 95066 Revision: 30-Jul-07



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Revision: 02-Oct-12 Document Number: 91000